

Notice of References Cited

Application/Control No.

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Applicant(s)/Patent Under
Reexamination
HAECKER ET AL.

Examiner

CHRISTINE T. MUI

Art Unit

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Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0051339	03-2003	Ehrfeld et al.	29/830
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	WO 01/72467	10-2001	WIPO	Ehrfeld et al	B23P 19/00
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	P					
	Q					
	R					
	S					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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